

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:

Name: Swa, Beng Hooi
E-mail: BH.Swa@fairchildsemi.com
Phone:

PCN Originator:

Name: Swa, Beng Hooi
E-mail: BH.Swa@fairchildsemi.com
Phone:

Implementation of change:

Expected 1st Device Shipment Date: 2011/10/03

Earliest Year/Work Week of Changed Product: 1141

Change Type Description: Alternate Fab Location, Wafer Diameter

Description of Change (From): The detector die component for random phase triacs and zero cross triacs from fabrication facility located in USA.

Description of Change (To): The detector die component for random phase triacs and zero cross triacs to alternate fabrication facility located in Taiwan and China respectively.

Reason for Change : Fairchild is qualifying alternate fabrication facilities to cater for increase demand and to provide die supply flexibility. This change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products. Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Qual/REL Plan Number(s): Q20080215, Q20080216, Q20100636

Qualification :

Passed

Results/Discussion for Qual Plan Number(s): Q20080215

Test: (Autoclave) Conditions: 100%RH, 121C Standard: JESD22-A102					
Lot	Device	96-HOURS	Failure Code		
Q20080215AAACLV	FODM3052	0/45			
Q20080215ABACLV	FODM3052	0/45			
Q20080215ACACLV	FODM3052	0/45			
Test: (High Temperature Op Life) Conditions: 100C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080215AAHTOL	FODM3052	0/45			
			0/45		
				0/45	
Q20080215ABHTOL		0/45			
			0/45		
				0/45	
Q20080215ACHTOL		0/45			
			0/45		
				0/45	
Test: (High Temperature Reverse Bias) Conditions: 100C, 480V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080215AAHTRB		0/45			
			0/45		
				0/45	
Q20080215ABHTRB		0/45			
			0/45		
				0/45	
Q20080215ACHTRB		0/45			
			0/45		
				0/45	
Test: (High Temperature Storage Life) Conditions: 150C Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080215AAHTSL		0/45			
			0/45		
				0/45	
Q20080215ABHTSL		0/45			
			0/45		
				0/45	
Q20080215ACHTSL		0/45			
			0/45		
				0/45	
Test: (Low Temperature Storage) Conditions: -55C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000	Failure Code
Q20080215AALTS		0/45			
			0/45		
				0/45	
Q20080215ABLTS		0/45			
			0/45		
				0/45	
Q20080215ACLTS		0/45			
			0/45		
				0/45	
Test: (Precondition) Conditions: Standard: JESSDSS-A113					
Lot	Device	Results	Failure Code		
Q20080215AAPCOPT01D	FODM3052	0/225			
Q20080215ABPCOPT01D	FODM3052	0/225			
Q20080215ACPCOPT01D	FODM3052	0/225			
Test: (Temperature Cycle) Conditions: -55C, 125C Standard: JESD22-A104					
Lot	Device	100-CYCLES	200-CYCLES	Failure Code	
Q20080215AATMCL1	FODM3052	0/45			
Q20080215AATMCL1	FODM3052		0/45		
Q20080215ABTMCL1	FODM3052	0/45			
Q20080215ABTMCL1	FODM3052		0/45		
Q20080215ACTMCL1	FODM3052	0/45			
Q20080215ACTMCL1	FODM3052		0/45		
Test: (Temperature Humidity Biased Test) Conditions: 85%RH, 85C, 100V Standard: JESD22-A101					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code

Q20080215AATHBT		0/45			
			0/45		
				0/45	
Q20080215ABTHBT		0/45			
			0/45		
				0/45	
Q20080215ACTHBT		0/45			
			0/45		
				0/45	

Results/Discussion for Qual Plan Number(s): Q20080216

Test: (Autoclave) Conditions: 100%RH, 121C Standard: JESD22-A102					
Lot	Device	96-HOURS	Failure Code		
Q20080216AAACLV	MOC3052M	0/45			
Q20080216ABACLV	MOC3052M	0/45			
Q20080216ACACLV	MOC3052M	0/45			
Test: (High Temperature Op Life) Conditions: 85C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080216AAHTOLA	MOC3052M	0/45			
			0/45		
				0/45	
Q20080216ABHTOLA		0/45			
			0/45		
				0/45	
Q20080216ACHTOLA		0/45			
			0/45		
				0/45	
Test: (High Temperature Reverse Bias) Conditions: 85C, 480V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080216AAHTRBA		0/45			
			0/45		
				0/45	
Q20080216ABHTRBA		0/45			
			0/45		
				0/45	
Q20080216ACHTRBA		0/45			
			0/45		
				0/45	
Test: (High Temperature Storage Life) Conditions: 150C Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080216AAHTSLA		0/45			
			0/45		
				0/45	
Q20080216ABHTSLA		0/45			
			0/45		
				0/45	
Q20080216ACHTSLA		0/45			
			0/45		
				0/45	
Test: (Low Temperature Storage) Conditions: -40C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000	Failure Code
Q20080216AALTSA		0/45			
			0/45		
				0/45	
Q20080216ABLTSA		0/45			
			0/45		
				0/45	
Q20080216ACLTSA		0/45			
			0/45		
				0/45	
Test: (Precondition) Conditions: Standard: JESD22-A113					
Lot	Device	Results	Failure Code		
Q20080216AAPCOPTO1BA	MOC3052M	0/225			
Q20080216ABPCOPTO1BA	MOC3052M	0/225			

Q20080216ACPCOPT01BA	MOC3052M	0/225			
Test: (Temperature Cycle) Conditions: -40C, 125C Standard: JESD22-A104					
Lot	Device	100-CYCLES	200-CYCLES	Failure Code	
Q20080216AATMCL1A	MOC3052M	0/45			
Q20080216AATMCL1A	MOC3052M		0/45		
Q20080216ABTMCL1A	MOC3052M	0/45			
Q20080216ABTMCL1A	MOC3052M		0/45		
Q20080216ACTMCL1A	MOC3052M	0/45			
Q20080216ACTMCL1A	MOC3052M		0/45		
Test: (Temperature Humidity Biased Test) Conditions: 85%RH, 85C, 100V Standard: JESD22-A101					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080216AATHBTA		0/45			
			0/45		
				0/45	
Q20080216ABTHBTA		0/45			
			0/45		
				0/45	
Q20080216ACTHBTA		0/45			
			0/45		
				0/45	

Results/Discussion for Qual Plan Number(s): Q20100636

Test: (High Temperature Op Life) Conditions: 100C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20100636AAHTOLA	FODM3062	0/22			
			0/22		
				0/22	
Q20100636ABHTOLA		0/77			
			0/77		
				0/77	
Q20100636ACHTOLA		0/77			
			0/77		
				0/77	
Q20100636ADHTOLA		0/77			
			0/77		
				0/77	
Test: (High Temperature Reverse Bias) Conditions: 100C, 480V Standard: JESD22-A108					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20100636AAHTRBA		0/22			
			0/22		
				0/22	
Q20100636ABHTRBA		0/77			
			0/77		
				0/77	
Q20100636ACHTRBA		0/77			
			0/77		
				0/77	
Q20100636ADHTRBA		0/77			
			0/77		
				0/77	
Test: (High Temperature Storage Life) Conditions: 150C Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20100636AAHTSLA		0/22			
			0/22		
				0/22	
Q20100636ABHTSLA		0/77			
			0/77		
				0/77	
Q20100636ACHTSLA		0/77			
			0/77		
				0/77	
Q20100636ADHTSLA		0/77			
			0/77		
				0/77	

Test: (Low Temperature Storage) Conditions: -40C Standard:					
Lot	Device	168-HOURS	500-HOURS	1000	Failure Code
Q20100636AALTSA		0/22			
			0/22		
				0/22	
Q20100636ABLTSA		0/77			
			0/77		
				0/77	
Q20100636ACLTSA		0/77			
			0/77		
				0/77	
Q20100636ADLTSA		0/77			
			0/77		
				0/77	
Test: (Precondition) Conditions: Standard: JESD22-A113					
Lot	Device	Results		Failure Code	
Q20100636AAPCOPT01EA	FODM3062	0/110			
Q20100636ABPCOPT01EA	FODM3062	0/385			
Q20100636ACPCOPT01EA	FODM3062	0/385			
Q20100636ADPCOPT01EA	FODM3062	0/385			
Test: (Temperature Cycle) Conditions: -55C, 125C Standard: JESD22-A104					
Lot	Device	100-CYCLES	200-CYCLES	Failure Code	
Q20100636AATMCL5A	FODM3062	0/22			
Q20100636AATMCL5A	FODM3062		0/22		
Q20100636ABTMCL5A	FODM3062	0/77			
Q20100636ABTMCL5A	FODM3062		0/77		
Q20100636ACTMCL5A	FODM3062	0/77			
Q20100636ACTMCL5A	FODM3062		0/77		
Q20100636ADTMCL5A	FODM3062	0/77			
Q20100636ADTMCL5A	FODM3062		0/77		
Test: (Temperature Humidity Biased Test) Conditions: 85%RH, 85C, 5V Standard: JESD22-A101					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20100636AATHBTA		0/22			
			0/22		
				0/22	
Q20100636ABTHBTA		0/77			
			0/77		
				0/77	
Q20100636ACTHBTA		0/77			
			0/77		
				0/77	
Q20100636ADTHBTA		0/77			
			0/77		
				0/77	

Product Id Description :

Affected FSIDs :

FODM3011R2_NF098	FODM3012R2V_NF098	FODM3012R2_NF098
FODM3012_NF098	FODM3022R2_NF098	FODM3022_NF098
FODM3023R2_NF098	FODM3023_NF098	FODM3062R2
FODM3062	FODM3063R2	FODM3063
FODM3082	FODM3083R2	FODM3083
H11PXM_9102D	H11ZXM_9107	MOC3010M
MOC3010SM	MOC3010SR2M	MOC3010SVM
MOC3010VM	MOC3011M	MOC3011SM
MOC3011SR2M	MOC3011SR2VM	MOC3011SVM
MOC3012M	MOC3012SM	MOC3012SR2M
MOC3012SVM	MOC3012TVM	MOC3012VM
MOC3020M	MOC3020SM	MOC3020SR2M

MOC3020TVM	MOC3021M	MOC3021SM
MOC3021SR2M	MOC3021SR2VM	MOC3021SVM
MOC3021TVM	MOC3021VM	MOC3022M
MOC3022SM	MOC3022SR2M	MOC3022SR2VM
MOC3022SVM	MOC3022TVM	MOC3022VM
MOC3023M	MOC3023SM	MOC3023SR2M
MOC3023SR2VM	MOC3023SVM	MOC3023TVM
MOC3023VM	MOC3031M	MOC3031SM
MOC3031SR2M	MOC3031VM	MOC3032M
MOC3032SM	MOC3032SR2M	MOC3032VM
MOC3033M	MOC3033SM	MOC3033SR2M
MOC3033SR2VM	MOC3033SVM	MOC3033VM
MOC3041M	MOC3041SM	MOC3041SR2M
MOC3041SR2VM	MOC3041SVM	MOC3041TVM
MOC3041VM	MOC3042M	MOC3042SM
MOC3042SR2M	MOC3042SR2VM	MOC3042SVM
MOC3042TVM	MOC3042VM	MOC3043M
MOC3043SM	MOC3043SR2M	MOC3043SR2VM
MOC3043SVM	MOC3043TVM	MOC3043VM
MOC3061M	MOC3061SM	MOC3061SR2M
MOC3061SR2VM	MOC3061SVM	MOC3061TVM
MOC3061VM	MOC3062M	MOC3062SM
MOC3062SR2M	MOC3062SR2VM	MOC3062SVM
MOC3062TVM	MOC3062VM	MOC3063M
MOC3063SM	MOC3063SR2M	MOC3063SR2VM
MOC3063SVM	MOC3063TVM	MOC3063VM
MOC3081M	MOC3081SM	MOC3081SR2M
MOC3081SVM	MOC3081TVM	MOC3082M
MOC3082SR2M	MOC3082SR2VM	MOC3082SVM
MOC3082TVM	MOC3082VM	MOC3083M
MOC3083SM	MOC3083SR2M	MOC3083SR2VM
MOC3083SVM	MOC3083TVM	MOC3083VM
MOC3162M	MOC3162SM	MOC3162VM
MOC3163M	MOC3163SM	MOC3163SR2M
MOC3163SVM	MOC3163TVM	